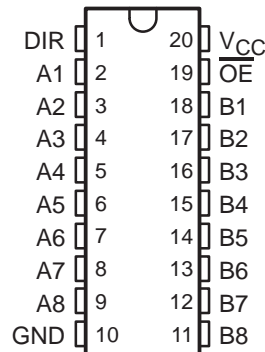


SN74LVCR2245A OCTAL BUS TRANSCEIVER WITH 3-STATE OUTPUTS

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- **EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process**
- **All Outputs Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required**
- **Typical V_{OLP} (Output Ground Bounce) $< 0.8\text{ V}$ at $V_{CC} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$**
- **Typical V_{OHV} (Output V_{OH} Undershoot) $> 2\text{ V}$ at $V_{CC} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$**
- **Power Off Disables Outputs, Permitting Live Insertion**
- **Supports Mixed-Mode Signal Operation on All Ports (5-V Input/Output Voltage With 3.3-V V_{CC})**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model ($C = 200\text{ pF}$, $R = 0$)**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages**

DB, DW, OR PW PACKAGE
(TOP VIEW)



description

This octal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74LVCR2245A is designed for asynchronous communication between data buses. The device transmits data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable (\overline{OE}) input can be used to disable the device so the buses are effectively isolated.

All outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74LVCR2245A is characterized for operation from -40°C to 85°C .



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

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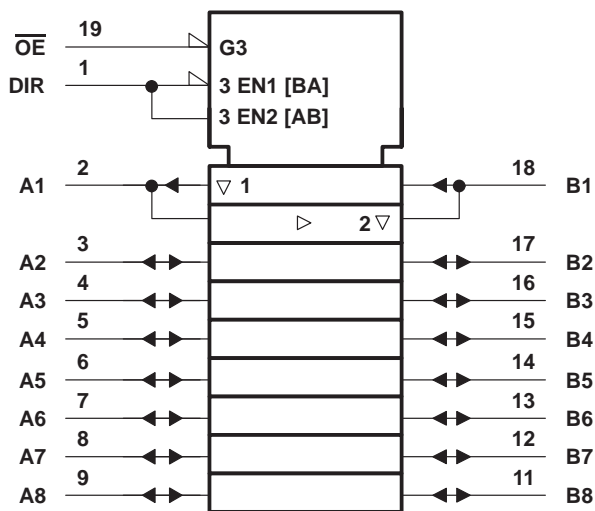
WITH 3-STATE OUTPUTS

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FUNCTION TABLE

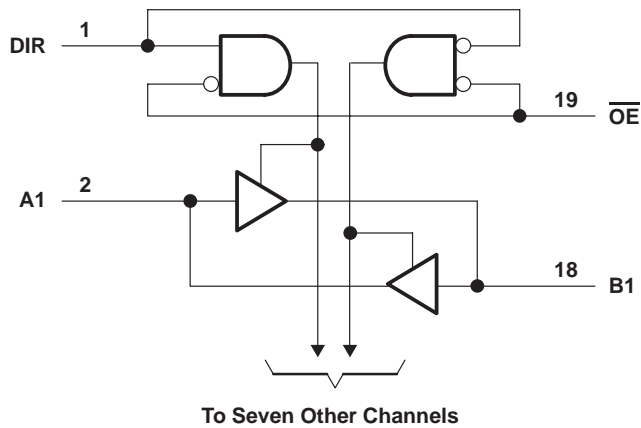
INPUTS		OPERATION
OE	DIR	
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC}	–0.5 V to 6.5 V
Input voltage range, V_I : (see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high-impedance or power-off state, V_O (see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high or low state, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DB package	115°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The value of V_{CC} is provided in the recommended operating conditions table.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC} Supply voltage	Operating	1.65	3.6	V
	Data retention only	1.5		
V_{IH} High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$		V
	$V_{CC} = 2.3$ V to 2.7 V	1.7		
	$V_{CC} = 2.7$ V to 3.6 V	2		
V_{IL} Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V		$0.35 \times V_{CC}$	V
	$V_{CC} = 2.3$ V to 2.7 V		0.7	
	$V_{CC} = 2.7$ V to 3.6 V		0.8	
V_I Input voltage		0	5.5	V
V_O Output voltage	High or low state	0	V_{CC}	V
	3 state	0	5.5	
I_{OH} High-level output current	$V_{CC} = 1.65$ V		–2	mA
	$V_{CC} = 2.3$ V		–4	
	$V_{CC} = 2.7$ V		–8	
	$V_{CC} = 3$ V		–12	
I_{OL} Low-level output current	$V_{CC} = 1.65$ V		2	mA
	$V_{CC} = 2.3$ V		4	
	$V_{CC} = 2.7$ V		8	
	$V_{CC} = 3$ V		12	
$\Delta t/\Delta v$ Input transition rise or fall rate		0	10	ns/V
T_A Operating free-air temperature		–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER				V _{CC}	MIN	TYP†	MAX	UNIT
V _{OH}			I _{OH} = −100 μA	1.65 V to 3.6 V	V _{CC} −0.2			V
			I _{OH} = −2 mA	1.65 V	1.2			
			I _{OH} = −4 mA	2.3 V	1.7			
				2.7 V	2.2			
			I _{OH} = −6 mA	3 V	2.4			
			I _{OH} = −8 mA	2.7 V	2			
		I _{OH} = −12 mA	3 V	2				
V _{OL}			I _{OL} = 100 μA	1.65 V to 3.6 V			0.2	V
			I _{OL} = 2 mA	1.65 V			0.45	
			I _{OL} = 4 mA	2.3 V			0.7	
				2.7 V			0.4	
			I _{OL} = 6 mA	3 V			0.55	
			I _{OL} = 8 mA	2.7 V			0.6	
		I _{OL} = 12 mA	3 V			0.8		
I _I	Control inputs	V _I = 0 to 5.5 V		3.6 V			±5	μA
I _{off}			V _I or V _O = 5.5 V	0			±10	μA
I _{OZ} ‡			V _O = 0 to 5.5 V	3.6 V			±10	μA
I _{CC}	V _I = V _{CC} or GND,		I _O = 0	3.6 V			10	μA
	3.6 V ≤ V _I ≤ 5.5 V§						10	
ΔI _{CC}			One input at V _{CC} − 0.6 V, Other inputs at V _{CC} or GND	2.7 V to 3.6 V			500	μA
C _i	Control inputs	V _I = V _{CC} or GND		3.3 V			4	pF
C _{io}	A or B ports	V _O = V _{CC} or GND		3.3 V			5.5	pF

† All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

‡ For I/O ports, the parameter I_{OZ} includes the input leakage current.

§ This applies in the disabled state only.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A or B	B or A	¶	¶	¶	¶	7.3		1.5	6.3	ns
t _{en}	$\overline{\text{OE}}$	A or B	¶	¶	¶	¶	9.5		1.5	8.2	ns
t _{dis}	$\overline{\text{OE}}$	A or B	¶	¶	¶	¶	8.5		1.7	7.8	ns
t _{sk(o)} #										1	ns

¶ This information was not available at the time of publication.

Skew between any two outputs of the same package switching in the same direction

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operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V ± 0.15 V	V _{CC} = 2.5 V ± 0.2 V	V _{CC} = 3.3 V ± 0.3 V	UNIT
				TYP	TYP	TYP	
C _{pd}	Power dissipation capacitance per transceiver	Outputs enabled	f = 10 MHz	†	†	48	pF
		Outputs disabled		†	†	4	

† This information was not available at the time of publication.

SN74LVCR2245A

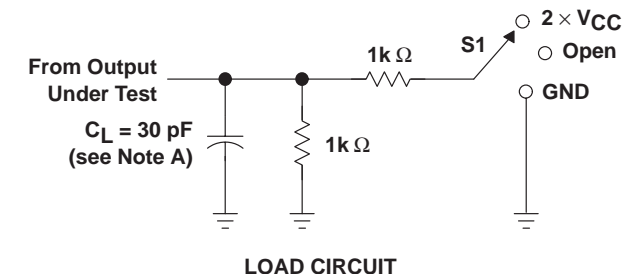
OCTAL BUS TRANSCEIVER

WITH 3-STATE OUTPUTS

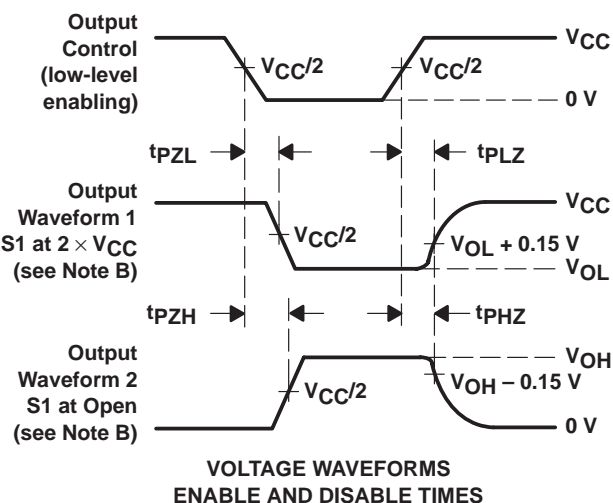
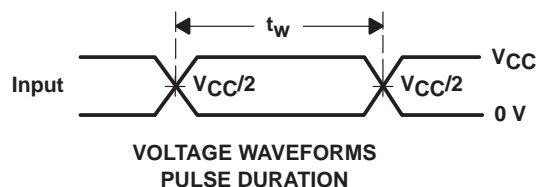
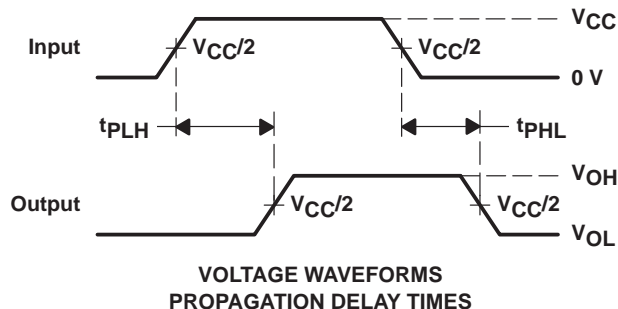
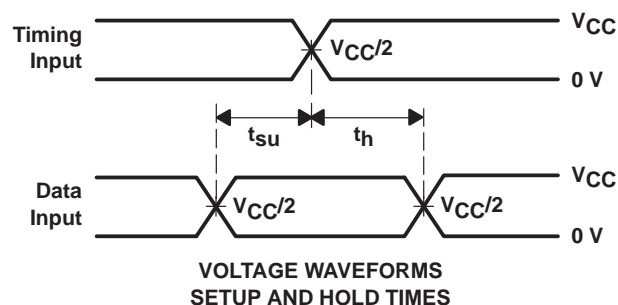
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PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	Open

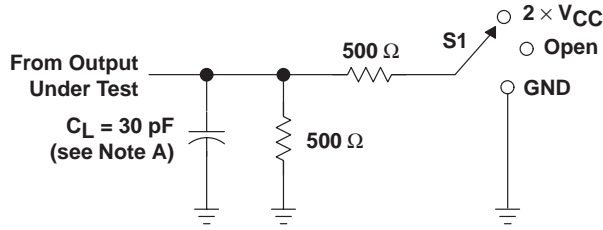


- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

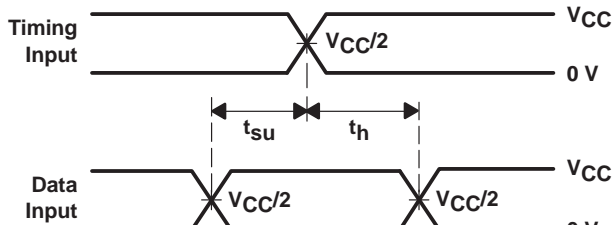
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

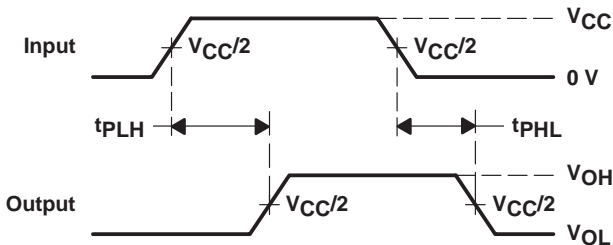


LOAD CIRCUIT

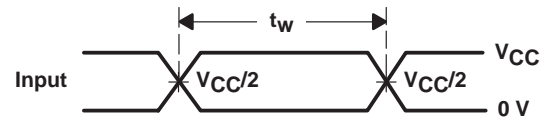
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PZH}	GND



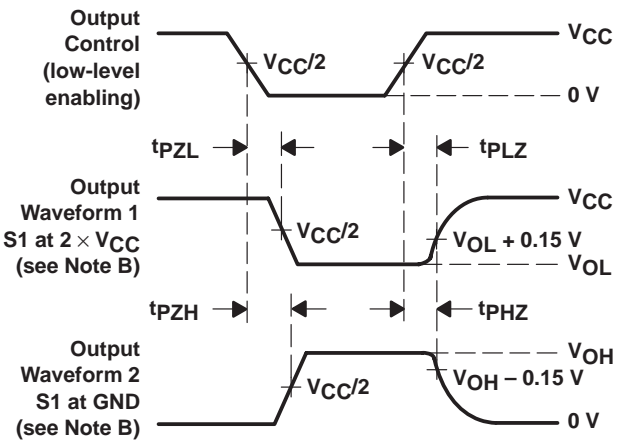
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION

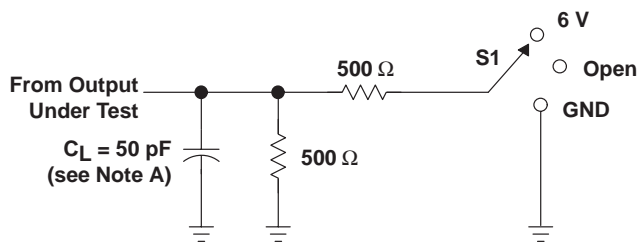


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

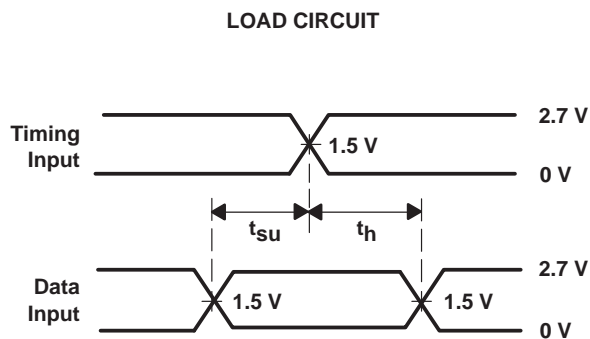
Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
 $V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

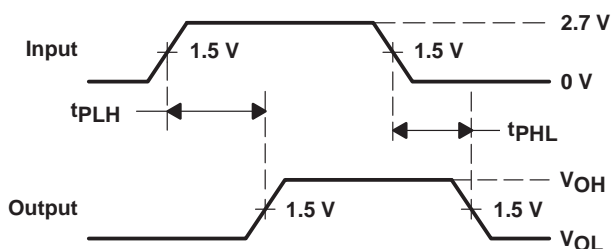


LOAD CIRCUIT

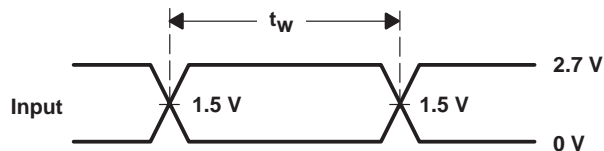
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



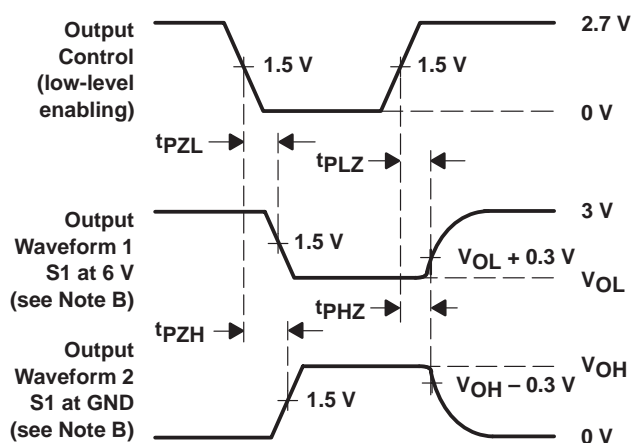
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
F. t_{PZL} and t_{PZH} are the same as t_{en} .
G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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